18. TEST PHOTOGRAPHS

See following Attached Pages for setup photographs.

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Figure 18-1
Ear Reference Point HAC Phantom Alignment (Standard Battery)

Figure 18-2
HAC Phantom Plane Alignment (Standard Battery)

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Figure 18-3
Ear Reference Point HAC Phantom Alignment (L-Battery Accessory)

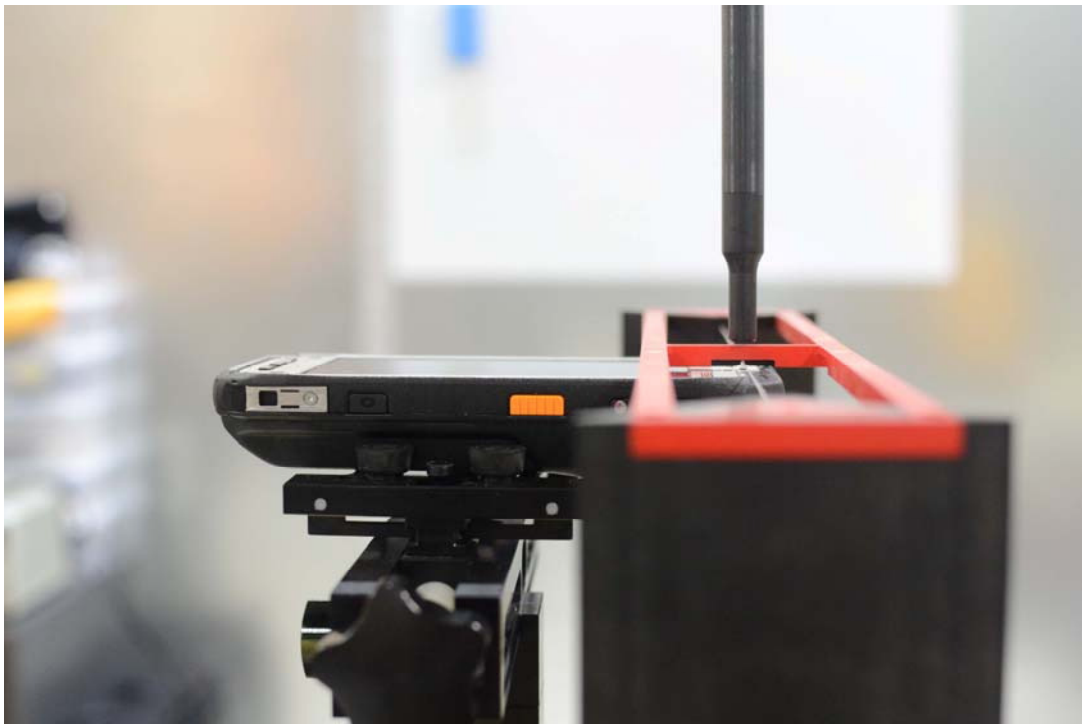

Figure 18-4
HAC Phantom Plane Alignment (L-Battery Accessory)

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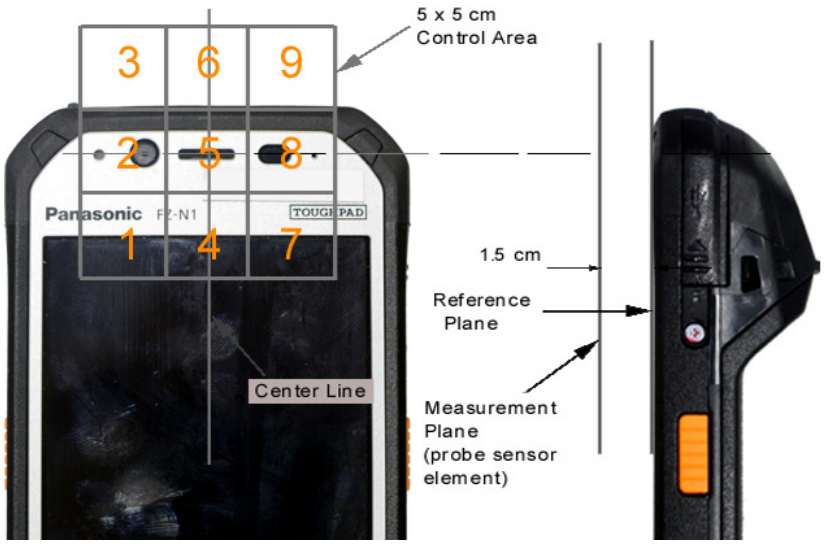

Figure 18-5 5x5 Scan grid above WD

Figure 18-6 E-Field WD Scan overlay

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